

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

FIS9-2001-02 US1

Application Number

10/035061

Applicant(s)

AUSSCHNITT ET AL.

Filing Date

12-28-2001

Group Art Unit

2877

U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | REF | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|----------------------|-----|-----------------|----------|-------------------|-------|----------|-------------------------------|
| W | | 5,805,290 | 09-08-98 | AUSSCHNITT ET AL. | | | |
| W | | 6,091,486 | 07-18-00 | KIRK | | | |
| ed | | 5,300,786 | 04-05-94 | BRUNNER ET AL. | | | |
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FOREIGN PATENT DOCUMENTS

| | REF | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | Translation | |
|--|-----|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | | YES | NO |
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
|----|--|---|
| W | | SPIE 3697 - "Application of blazed gratings for determination of equivalent primary azimuthal aberrations" - Kirk and Progler - Proceedings SPIE, Vol. 3679, pp. 70 - 76, Date of Publication 1999, USA |
| | | SPIE 4000 - "Impact of high order aberrations on the performance of the aberration monitor" - Dirksen et al. - Proceedings SPIE, Vol. 4000, pp. 9 - 17, Date of Publication 2000, USA |
| ND | | SPIE 4000 - "In-situ measurement of lens aberrations" - Farrar et al. - Proceedings SPIE, Vol. 4000, pp. 18 - 29, Date of Publication 2000, USA |

EXAMINER

Michael Stahl

DATE CONSIDERED

11-15-04
2-25-04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

* The following were not considered since they failed to provide a date of publication.